

## DESCRIPTION

These miniature surface mount MOSFETs utilize a high cell density trench process to provide low  $R_{DS(on)}$  and to ensure minimal power loss and heat dissipation. Typical applications are DC-DC converters and power management in portable and battery-powered products such as computers, printers, PCMCIA cards, cellular and cordless telephones.

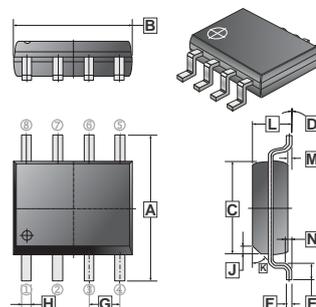
## FEATURES

- Low  $R_{DS(on)}$  provides higher efficiency and extends battery life.
- Low thermal impedance copper leadframe SOP-8 saves board space.
- Fast switching speed.
- High performance trench technology.

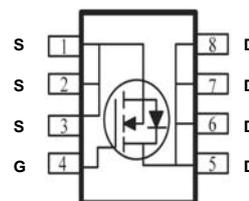
## PACKAGE INFORMATION

Package	MPQ	LeaderSize
SOP-8	2.5K	13' inch

### SOP-8



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	5.80	6.20	H	0.35	0.49
B	4.80	5.00	J	0.375 REF.	
C	3.80	4.00	K	45°	
D	0°	8°	L	1.35	1.75
E	0.40	0.90	M	0.10	0.25
F	0.19	0.25	N	0.25 REF.	
G	1.27 TYP.				



## MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>1</sup>	$I_D @ T_A = 25^\circ\text{C}$	$\pm 13$	A
	$I_D @ T_A = 70^\circ\text{C}$	$\pm 11$	A
Pulsed Drain Current <sup>2</sup>	$I_{DM}$	$\pm 50$	A
Continuous Source Current (Diode Conduction) <sup>1</sup>	$I_S$	2.3	A
Total Power Dissipation <sup>1</sup>	$P_D @ T_A = 25^\circ\text{C}$	3.1	W
	$P_D @ T_A = 70^\circ\text{C}$	2.2	W
Operating Junction & Storage Temperature Range	$T_J, T_{STG}$	-55 ~ 150	$^\circ\text{C}$
<b>Thermal Resistance Ratings</b>			
Thermal Resistance Junction-Case (Max.) <sup>1</sup>	$t \leq 5 \text{ sec}$	$R_{\theta JC}$	25 $^\circ\text{C} / \text{W}$
Thermal Resistance Junction-Ambient (Max.) <sup>1</sup>	$t \leq 5 \text{ sec}$	$R_{\theta JA}$	50 $^\circ\text{C} / \text{W}$

### Notes

- 1 Surface Mounted on 1" x 1" FR4 Board.
- 2 Pulse width limited by maximum junction temperature.

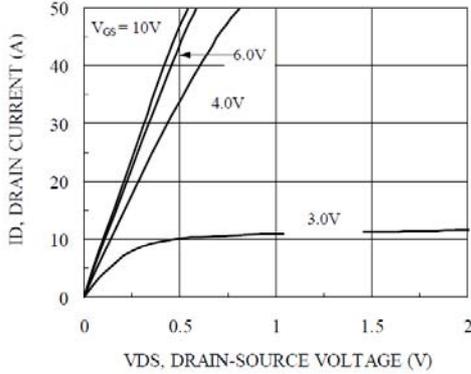
**ELECTRICAL CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>Static</b>						
Gate-Threshold Voltage	$V_{GS(th)}$	1	-	-	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu\text{A}$
Gate-Body Leakage	$I_{GSS}$	-	-	$\pm 100$	nA	$V_{DS} = 0\text{V}$ , $V_{GS} = 20\text{V}$
Zero Gate Voltage Drain Current	$I_{DSS}$	-	-	1	$\mu\text{A}$	$V_{DS} = 24\text{V}$ , $V_{GS} = 0\text{V}$
		-	-	25	$\mu\text{A}$	$V_{DS} = 24\text{V}$ , $V_{GS} = 0\text{V}$ , $T_J = 55^\circ\text{C}$
On-State Drain Current <sup>1</sup>	$I_{D(on)}$	20	-	-	A	$V_{DS} = 5\text{V}$ , $V_{GS} = 10\text{V}$
Drain-Source On-Resistance <sup>1</sup>	$R_{DS(ON)}$	-	-	13.5	m $\Omega$	$V_{GS} = 10\text{V}$ , $I_D = 10\text{A}$
		-	-	20		$V_{GS} = 4.5\text{V}$ , $I_D = 8\text{A}$
Forward Transconductance <sup>1</sup>	$g_{fs}$	-	40	-	S	$V_{DS} = 15\text{V}$ , $I_D = 10\text{A}$
Diode Forward Voltage	$V_{SD}$	-	0.7	-	V	$I_S = 2.3\text{A}$ , $V_{GS} = 0\text{V}$
<b>Dynamic <sup>2</sup></b>						
Total Gate Charge	$Q_g$	-	12.5	-	nC	$I_D = 10\text{A}$ $V_{DS} = 15\text{V}$ $V_{GS} = 4.5\text{V}$
Gate-Source Charge	$Q_{gs}$	-	2.6	-		
Gate-Drain Charge	$Q_{gd}$	-	4.6	-		
Input Capacitance	$C_{ISS}$		1191		pF	$f = 1\text{MHz}$ $V_{DS} = 15\text{V}$ $V_{GS} = 0\text{V}$
Output Capacitance	$C_{OSS}$		412			
Reverse Transfer Capacitance	$C_{RSS}$		160			
Turn-On Delay Time	$T_{d(on)}$	-	20	-	nS	$V_{DD} = 25\text{V}$ $I_D = 1\text{A}$ $V_{GEN} = 10\text{V}$ $R_L = 25\Omega$
Rise Time	$T_r$	-	9	-		
Turn-Off Delay Time	$T_{d(off)}$	-	70	-		
Fall Time	$T_f$	-	20	-		

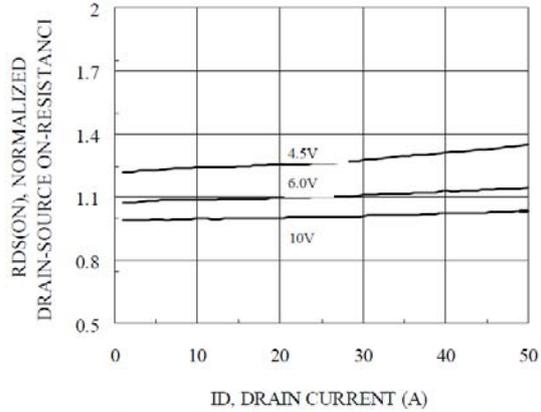
Notes

- 1 Pulse test :  $PW \leq 300\mu\text{s}$  duty cycle  $\leq 2\%$ .
- 2 Guaranteed by design, not subject to production testing.

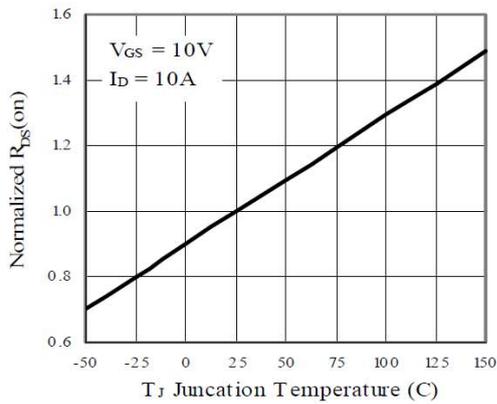
**CHARACTERISTICS CURVE**



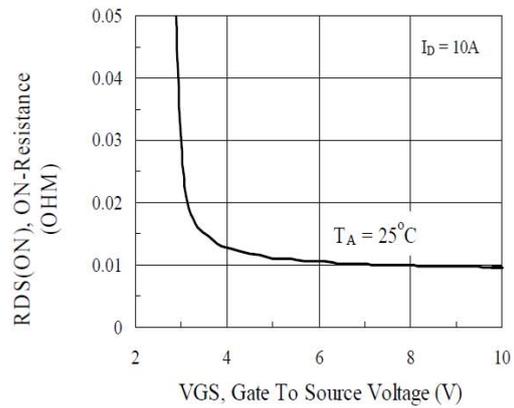
**Figure 1. On-Region Characteristics**



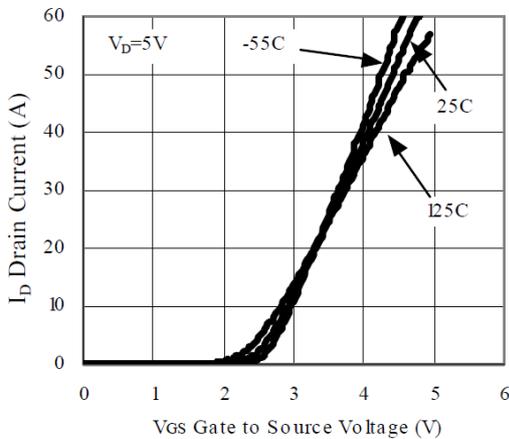
**Figure 2. On-Resistance with Drain Current**



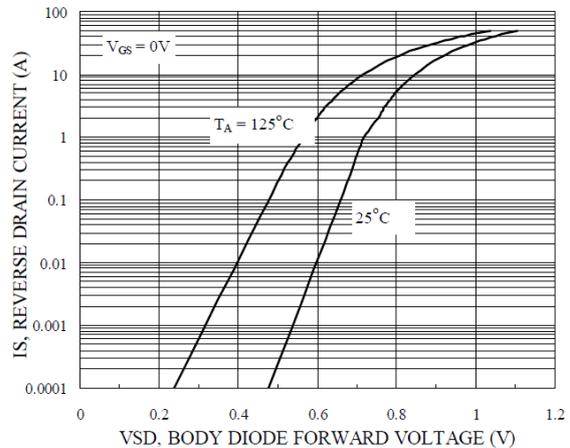
**Figure 3. On-Resistance Variation with Temperature**



**Figure 4. On-Resistance Variation with Gate to Source Voltage**



**Figure 5. Transfer Characteristics**



**Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature**

**CHARACTERISTICS CURVE**

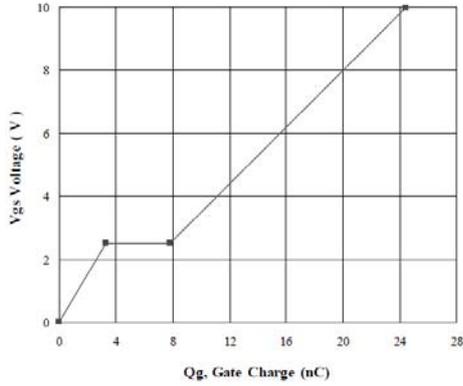


Figure 7. Gate Charge Characteristics

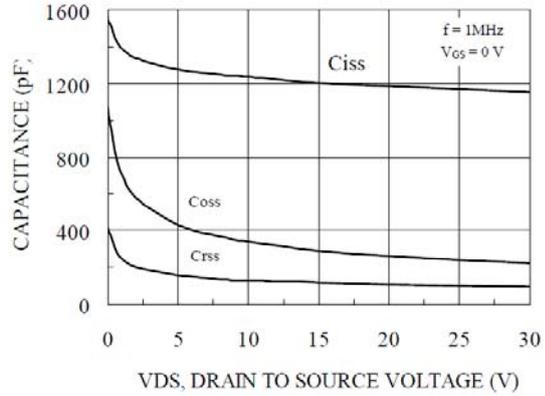


Figure 8. Capacitance Characteristics

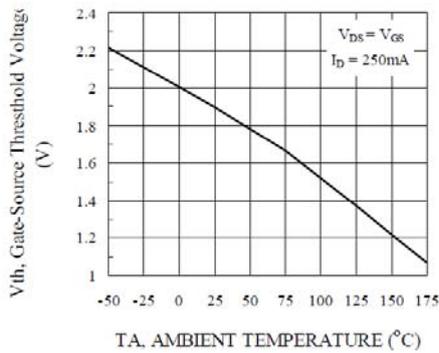


Figure 9. Threshold Vs Ambient Temperature

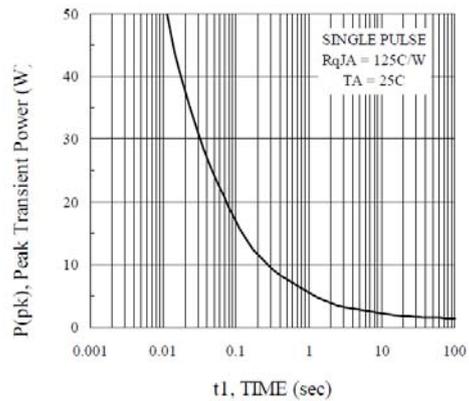


Figure 10. Single Pulse Maximum Power Dissipation

**Normalized Thermal Transient Junction to Ambient**

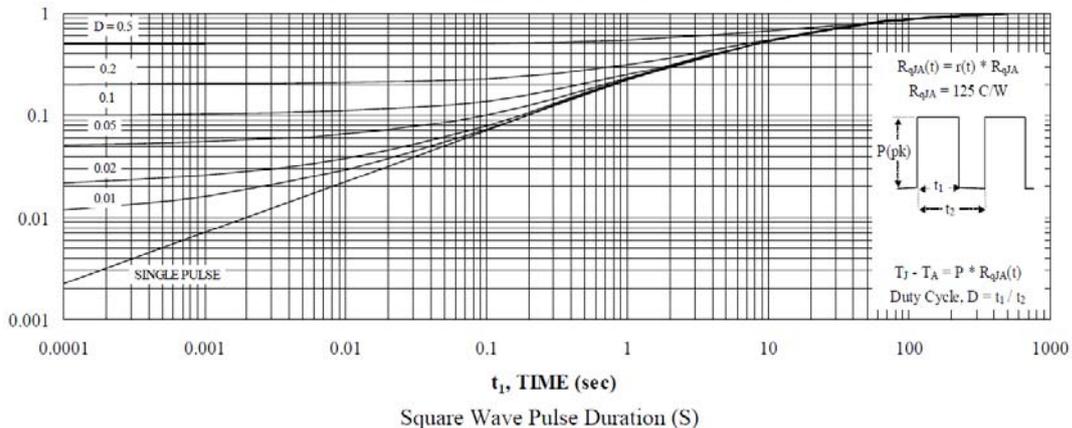


Figure 11. Transient Thermal Response Curve